TOSHIBA Power MOS FET Module Silicon P Channel MOS Type (L²- π -MOSV 4 in 1)

MP4211

High Power, High Speed Switching Applications For Printer Head Pin Driver and Pulse Motor Driver For Solenoid Driver

- 4 V gate drive available
- Small package by full molding (SIP 10 pin)
- High drain power dissipation (4 devices operation) : $P_T = 4 \text{ W} (T_a = 25^{\circ}\text{C})$
- Low drain-source ON resistance: RDS (ON) = 0.16Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 4.0 \text{ S}$ (typ.)
- Low leakage current: I_{GSS} = $\pm 10 \ \mu A \ (max) \ (V_{GS} = \pm 16 \ V)$ I_{DSS} = $-100 \ \mu A \ (max) \ (V_{DS} = -60 \ V)$
- Enhancement-mode: V_{th} = -0.8 to -2.0 V (V_{DS} = -10 V, I_D = -1 mA)

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	-60	V	
Drain-gate voltage (R_{GS} = 20 k Ω)		V _{DGR}	-60	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC	I _D	-5	А	
Drain current	Pulse	I _{DP}	-20	~	
Drain power dissipation (1 device operation, Ta = 25°C)		PD	2.0	W	
Drain power dissipation (4 devices operation, Ta	= 25°C)	P _{DT}	4.0	W	
Single pulse avalanche e	energy (Note 1)	E _{AS}	273	mJ	
Avalanche current		I _{AR}	-5	А	
Repetitive avalanche energy (Note 2)	1 device operation	E _{AR}	0.2	mJ	
	4 devices operation	E _{ART}	0.4	IIIJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	

Note 1: Avalanche energy (single pulse) applied condition $V_{DD} = -25 \text{ V}$, starting $T_{ch} = 25^{\circ}\text{C}$, L = 14.84 mH, R_G = 25 Ω , I_{AR} = -5 A

Note 2: Repetitive rating; pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device. Please handle with caution.







Weight: 2.1 g (typ.)

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Array Configuration



Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance of channel to ambient	ΣR _{th (ch-a)}	31.2	°C/W	
(4 devices operation, Ta = 25°C)	(
Maximum lead temperature for soldering purposes	TL	260	°C	
(3.2 mm from case for t = 10 s)				

Electrical Characteristics (Ta = 25°C)

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V	_	_	±10	μA
Drain cut-off curr	ent	I _{DSS}	V_{DS} = -60 V, V_{GS} = 0 V	-		-100	μA
Drain-source brea	akdown voltage	V (BR) DSS	$I_{D} = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-60		-	V
Gate threshold vo	oltage	V _{th}	V _{DS} = -10 V, I _D = -1 mA	-0.8	_	-2.0	V
Drain-source ON resistance		P-a (av)	V _{GS} = -4 V, I _D = -2.5 A	_	0.24	0.28	Ω
		R _{DS (ON)}	V_{GS} = -10 V, I _D = -2.5 A	-	0.16	0.19	
Forward transfer	admittance	Y _{fs}	V _{DS} = -10 V, I _D = -2.5 A	2.0	4.0	-	S
Input capacitance		C _{iss}		_	630	_	pF
Reverse transfer capacitance		C _{rss}	V _{DS} = -10 V, V _{GS} = 0 V, f = 1 MHz	_	95	_	pF
Output capacitance		C _{oss}			290	_	pF
Switching time	Rise time	t _r	V_{GS} -10 V C_{GS} -10 V C_{G} T_{T}	_	25	_	
	Turn-on time	t _{on}			45	_	
	Fall time	t _f		_	55	_	ns
	Turn-off time	t _{off}		l	200	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	22	_	nC
Gate-source charge		Q _{gs}	V _{DD} ≈ −48 V, V _{GS} = −10 V, I _D = −5 A	_	16	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	6	_	nC

Source-Drain Diode Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current	I _{DR}	—	_	_	-5	А
Pulse drain reverse current	I _{DRP}	—		—	-20	А
Diode forward voltage	V _{DSF}	$I_{DR} = -5 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$		—	1.7	V
Reverse recovery time	t _{rr}	I _{DR} = -5 A, V _{GS} = 0 V	_	80	_	ns
Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 50 A/µs	_	0.1	_	μC

Marking



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